



Short Course on Microwave Measurements

Nov. 30th - Dec. 1st, 2010
Clearwater, Florida



AGENDA

Tuesday, November 30th

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 8:10 a.m. **Welcome and Introduction**
Dominique Schreurs – K.U.Leuven
- 8:10 a.m. – 9:00 a.m. **Millimetre-wave Connectorized S-Parameter Measurements**
Jon Martens – Anritsu
- 9:00 a.m. – 9:50 a.m. **Measurement Verification at Millimetre-wave Frequencies**
Ron Ginley – NIST
- 9:50 a.m. – 10:20 a.m. **Break**
- 10:20 a.m. – 11:10 a.m. **Millimetre-wave On-Wafer S-Parameter Measurements**
Dylan Williams – NIST
- 11:10 a.m. – 12:00 p.m. **Measurement Uncertainty**
Nick Ridler – NPL
- 12:00 p.m. – 1:00 p.m. **Lunch**
- 1:00 p.m. – 1:50 p.m. **Uncertainties in On-Wafer S-parameter Measurements**
Uwe Arz – PTB
- 1:50 p.m. – 2:40 p.m. **Microwave and Millimetre-wave Noise Measurements**
Larry Dunleavy – University of South Florida
- 2:40 p.m. – 3:10 p.m. **Break**
- 3:10 p.m. – 4:00 p.m. **VNA Measurement misconceptions**
Dave Blackham – Agilent
- 4:00 p.m. – 5:00 p.m. **'Bring your problem'**
All instructors

Wednesday, December 1st

- 8:00 a.m. – 8:50 a.m. **Microwave and Millimetre-wave Power Measurements**
Tom Crowley – NIST
- 8:50 a.m. – 9:40 a.m. **Non-linear Measurements**
Dominique Schreurs – K.U.Leuven
- 9:40 a.m. – 10:10 a.m. **Break**
- 10:10 a.m. – 11:00 a.m. **High Speed Oscilloscope Measurements**
Paul Hale – NIST
- 11:00 a.m. – 11:50 a.m. **Sub-millimetre-wave Measurements**
Nick Ridler – NPL and Ron Ginley – NIST
- 11:50 a.m. – 12:00 p.m. **Wrap-up**

Contact

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